

# Complementary MOSFET

## ELM16601EA-S

### ■General Description

ELM16601EA-S uses advanced trench technology to provide excellent  $R_{ds(on)}$  and low gate charge.

### ■Features

- |  |   |
|--|---|
| N-channel                              | P-channel                               |
| $V_{ds}=30V$                           | $V_{ds}=-30V$                           |
| $I_d=3.4A(V_{gs}=10V)$                 | $I_d=-2.3A(V_{gs}=-10V)$                |
| $R_{ds(on)} < 60m\Omega(V_{gs}=10V)$   | $R_{ds(on)} < 135m\Omega(V_{gs}=-10V)$  |
| $R_{ds(on)} < 75m\Omega(V_{gs}=4.5V)$  | $R_{ds(on)} < 185m\Omega(V_{gs}=-4.5V)$ |
| $R_{ds(on)} < 115m\Omega(V_{gs}=2.5V)$ | $R_{ds(on)} < 265m\Omega(V_{gs}=-2.5V)$ |

### ■Maximum Absolute Ratings

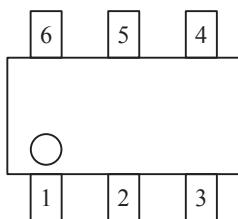
Parameter	Symbol	N-ch (Max.)	P-ch (Max.)	Unit	Note
Drain-source voltage	$V_{ds}$	30	-30	V	
Gate-source voltage	$V_{gs}$	$\pm 12$	$\pm 12$	V	
Continuous drain current	$I_d$	3.4	-2.3	A	1
		2.7	-1.8		
Pulsed drain current	$I_{dm}$	30	-30	A	2
Power dissipation	$P_d$	1.15	1.15	W	
		0.73	0.73		
Junction and storage temperature range	$T_j, T_{stg}$	-55 to 150	-55 to 150	°C	

### ■Thermal Characteristics

Parameter	Symbol	Device	Typ.	Max.	Unit	Note
Maximum junction-to-ambient	$R_{\theta ja}$	N-ch	78	110	°C/W	1
Maximum junction-to-ambient			106	150	°C/W	
Maximum junction-to-lead			64	80	°C/W	3
Maximum junction-to-ambient	$R_{\theta ja}$	P-ch	78	110	°C/W	1
Maximum junction-to-ambient			106	150	°C/W	
Maximum junction-to-lead			64	80	°C/W	3

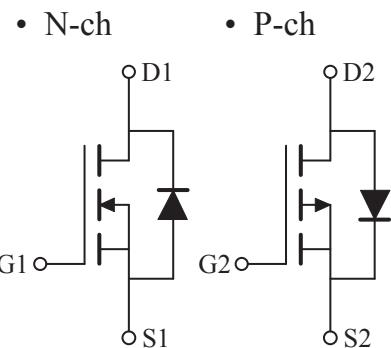
### ■Pin configuration

SOT-26(TOP VIEW)



Pin No.	Pin name
1	GATE1
2	SOURCE2
3	GATE2
4	DRAIN2
5	SOURCE1
6	DRAIN1

### ■Circuit



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### ■Electrical Characteristics (N-ch)

T<sub>a</sub>=25°C

Parameter	Symbol	Conditions		Min.	Typ.	Max.	Unit	
<b>STATIC PARAMETERS</b>								
Drain-source breakdown voltage	BV <sub>dss</sub>	Id=250μA, V <sub>gs</sub> =0V		30			V	
Zero gate voltage drain current	Id <sub>ss</sub>	V <sub>ds</sub> =24V, V <sub>gs</sub> =0V	T <sub>j</sub> =55°C			1	μA	
						5		
Gate-body leakage current	I <sub>gss</sub>	V <sub>ds</sub> =0V, V <sub>gs</sub> =±12V				100	nA	
Gate threshold voltage	V <sub>gs(th)</sub>	V <sub>ds</sub> =V <sub>gs</sub> , Id=250μA		0.6	1.0	1.4	V	
On state drain current	Id(on)	V <sub>gs</sub> =4.5V, V <sub>ds</sub> =5V		10			A	
Static drain-source on-resistance	R <sub>ds(on)</sub>	V <sub>gs</sub> =10V, Id=3A	T <sub>j</sub> =125°C		50	60	mΩ	
					75			
		V <sub>gs</sub> =4.5V, Id=3A			60	75		
Forward transconductance	G <sub>fs</sub>	V <sub>ds</sub> =5V, Id=3A			88	115	S	
					7.8			
					0.8	1.0	V	
Diode forward voltage	V <sub>sd</sub>	I <sub>s</sub> =1A, V <sub>gs</sub> =0V					A	
<b>DYNAMIC PARAMETERS</b>								
Input capacitance	C <sub>iss</sub>	V <sub>gs</sub> =0V, V <sub>ds</sub> =15V, f=1MHz			390.0		pF	
Output capacitance	C <sub>oss</sub>				54.5		pF	
Reverse transfer capacitance	C <sub>rss</sub>				41.0		pF	
Gate resistance	R <sub>g</sub>	V <sub>gs</sub> =0V, V <sub>ds</sub> =0V, f=1MHz			3		Ω	
<b>SWITCHING PARAMETERS</b>								
Total gate charge	Q <sub>g</sub>	V <sub>gs</sub> =4.5V, V <sub>ds</sub> =15V, Id=3A			4.34		nC	
Gate-source charge	Q <sub>gs</sub>				1.38		nC	
Gate-drain charge	Q <sub>gd</sub>				0.60		nC	
Turn-on delay time	t <sub>d(on)</sub>	V <sub>gs</sub> =10V, V <sub>ds</sub> =15V R <sub>l</sub> =5Ω, R <sub>gen</sub> =6Ω			4		ns	
Turn-on rise time	t <sub>r</sub>				2		ns	
Turn-off delay time	t <sub>d(off)</sub>				22		ns	
Turn-off fall time	t <sub>f</sub>				3		ns	
Body-diode reverse recovery time	t <sub>rr</sub>	I <sub>f</sub> =3A, dI/dt=100A/μs			11.0		ns	
Body-diode reverse recovery charge	Q <sub>rr</sub>	I <sub>f</sub> =3A, dI/dt=100A/μs			5.5		nC	

#### NOTE :

1. The value of R<sub>θja</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board of 2oz. Copper, in still air environment with T<sub>a</sub>=25°C. The value in any given applications depends on the user's specific board design, The current rating is based on the t ≤ 10s thermal resistance rating.
2. Repetitive rating, pulse width limited by junction temperature.
3. The R<sub>θja</sub> is the sum of the thermal impedance from junction to lead R<sub>θjl</sub> and lead to ambient.
4. The static characteristics in Figures 1 to 6 are obtained using 80μs pulses, duty cycle 0.5%max.
5. These tests are performed with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>a</sub>=25°C. The SOA curve provides a single pulse rating.



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## ■ Typical Electrical and Thermal Characteristics (N-ch)

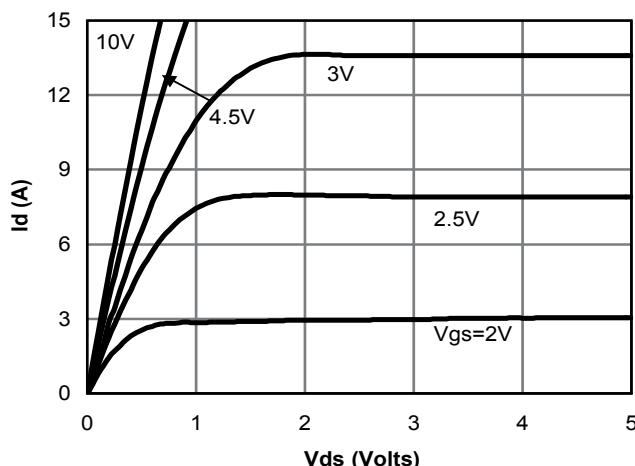


Fig 1: On-Region Characteristics

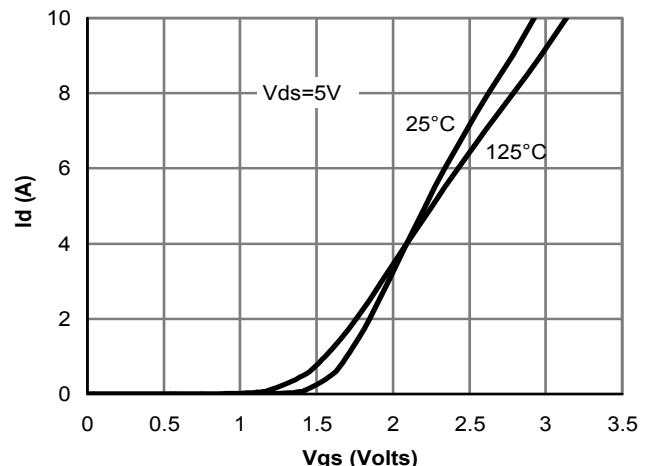


Figure 2: Transfer Characteristics

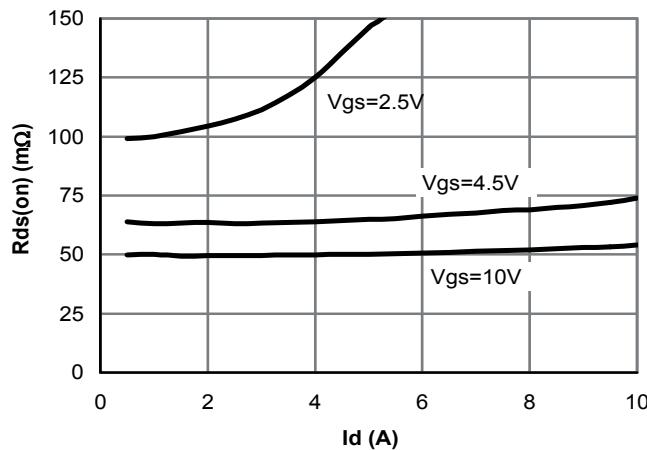


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

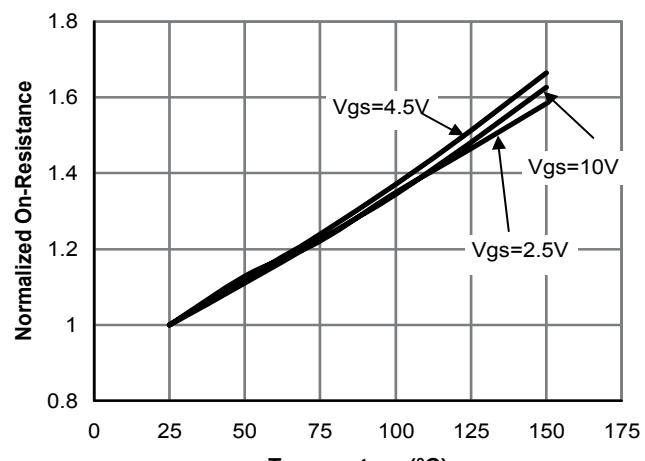


Figure 4: On-Resistance vs. Junction Temperature

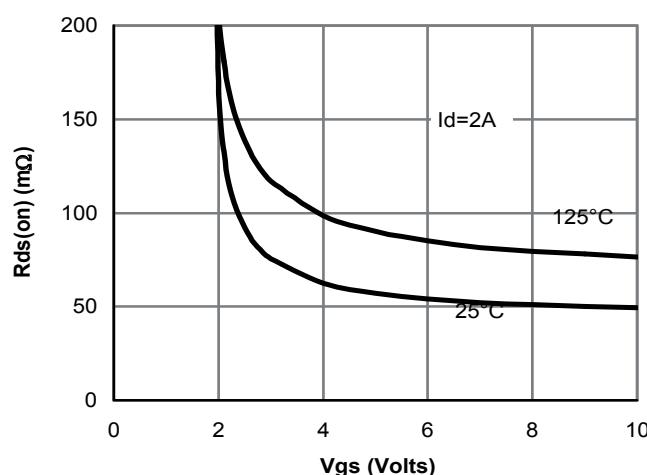


Figure 5: On-Resistance vs. Gate-Source Voltage

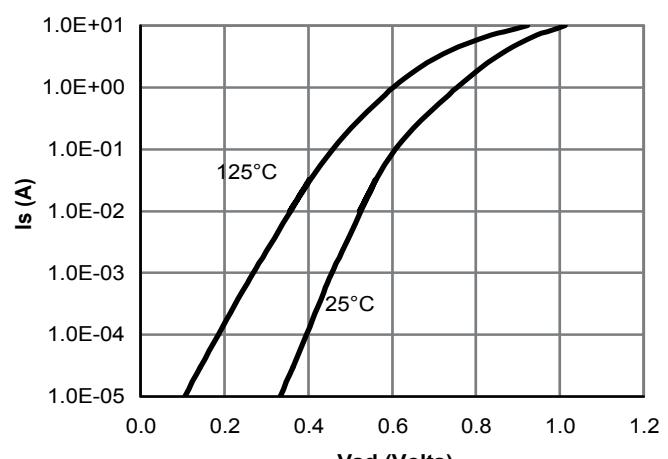


Figure 6: Body-Diode Characteristics

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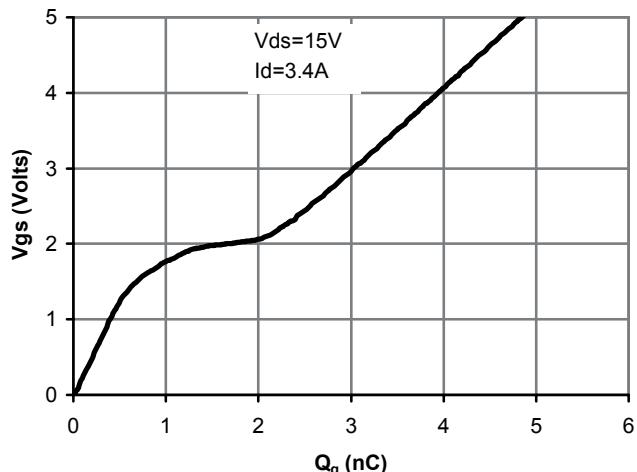


Figure 7: Gate-Charge Characteristics

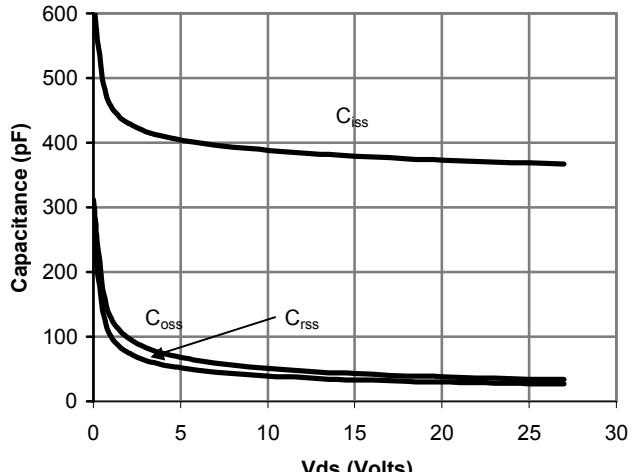


Figure 8: Capacitance Characteristics

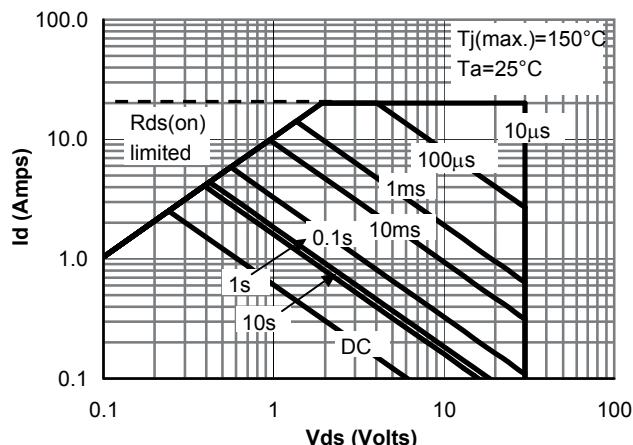


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

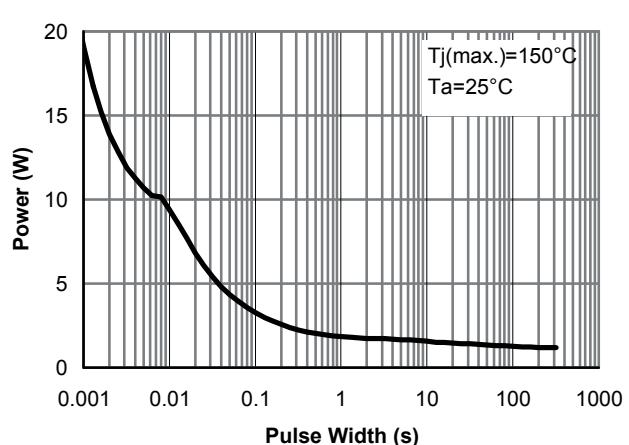


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

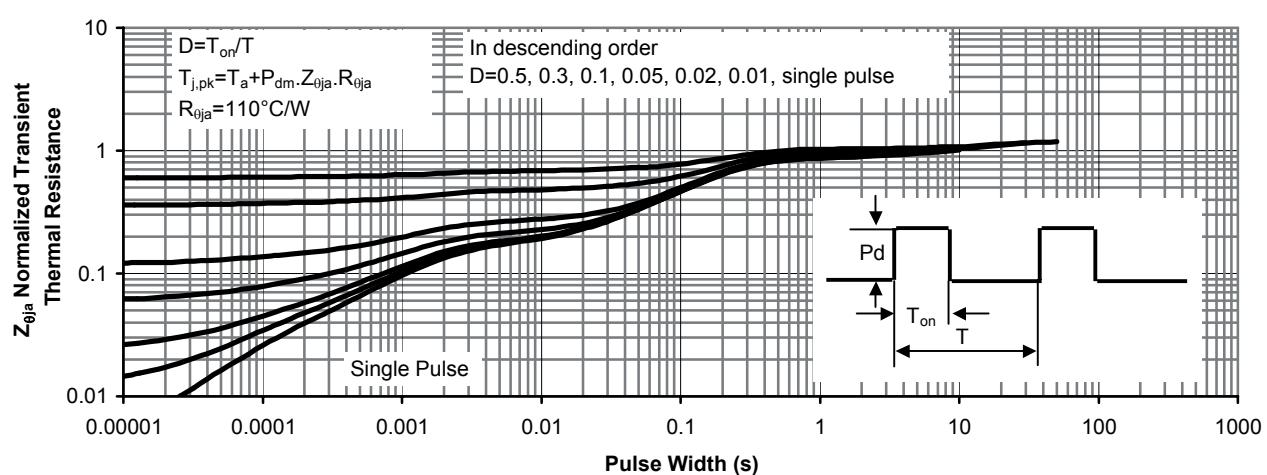


Figure 11: Normalized Maximum Transient Thermal Impedance

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### ■Electrical Characteristics (P-ch)

T<sub>a</sub>=25°C

Parameter	Symbol	Conditions		Min.	Typ.	Max.	Unit	
<b>STATIC PARAMETERS</b>								
Drain-source breakdown voltage	BV <sub>dss</sub>	Id=-250μA, V <sub>gs</sub> =0V		-30			V	
Zero gate voltage drain current	Id <sub>ss</sub>	V <sub>ds</sub> =-24V, V <sub>gs</sub> =0V	T <sub>j</sub> =55°C			-1	μA	
						-5		
Gate-body leakage current	I <sub>gss</sub>	V <sub>ds</sub> =0V, V <sub>gs</sub> =±12V				±100	nA	
Gate threshold voltage	V <sub>gs(th)</sub>	V <sub>ds</sub> =V <sub>gs</sub> , Id=-250μA		-0.6	-1.0	-1.4	V	
On state drain current	Id(on)	V <sub>gs</sub> =-4.5V, V <sub>ds</sub> =-5V		-10			A	
Static drain-source on-resistance	R <sub>ds(on)</sub>	V <sub>gs</sub> =-10V, Id=-2.3A	T <sub>j</sub> =125°C		107	135	mΩ	
		V <sub>gs</sub> =-4.5V, Id=-2A			135	185	mΩ	
		V <sub>gs</sub> =-2.5V, Id=-1A			195	265	mΩ	
Forward transconductance	G <sub>fs</sub>	V <sub>ds</sub> =-5V, Id=-2.3A			8		S	
Diode forward voltage	V <sub>sd</sub>	Is=-1A, V <sub>gs</sub> =0V			-0.85	-1.00	V	
Max. body-diode continuous current	Is					-1.35	A	
<b>DYNAMIC PARAMETERS</b>								
Input capacitance	C <sub>iss</sub>	V <sub>gs</sub> =0V, V <sub>ds</sub> =-15V, f=1MHz			409		pF	
Output capacitance	C <sub>oss</sub>				55		pF	
Reverse transfer capacitance	C <sub>rss</sub>				42		pF	
Gate resistance	R <sub>g</sub>	V <sub>gs</sub> =0V, V <sub>ds</sub> =0V, f=1MHz			12		Ω	
<b>SWITCHING PARAMETERS</b>								
Total gate charge	Q <sub>g</sub>	V <sub>gs</sub> =-4.5V, V <sub>ds</sub> =-15V Id=-2.5A			4.80		nC	
Gate-source charge	Q <sub>gs</sub>				1.34		nC	
Gate-drain charge	Q <sub>gd</sub>				0.72		nC	
Turn-on delay time	t <sub>d(on)</sub>	V <sub>gs</sub> =-10V, V <sub>ds</sub> =-15V R <sub>l</sub> =6Ω, R <sub>gen</sub> =6Ω			13		ns	
Turn-on rise time	t <sub>r</sub>				10		ns	
Turn-off delay time	t <sub>d(off)</sub>				28		ns	
Turn-off fall time	t <sub>f</sub>				13		ns	
Body diode reverse recovery time	t <sub>rr</sub>	I <sub>f</sub> =-2.5A, dI/dt=100A/μs			26.0		ns	
Body diode reverse recovery charge	Q <sub>rr</sub>	I <sub>f</sub> =-2.5A, dI/dt=100A/μs			15.6		nC	

#### NOTE :

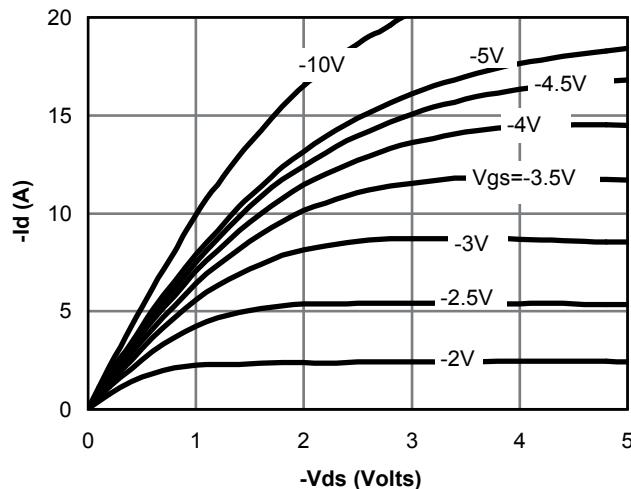
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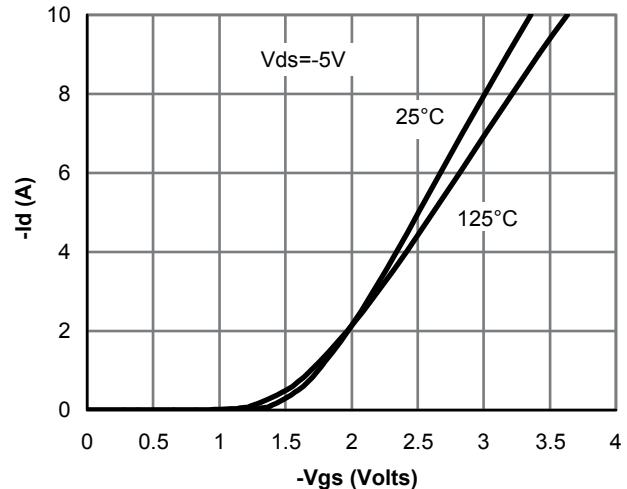
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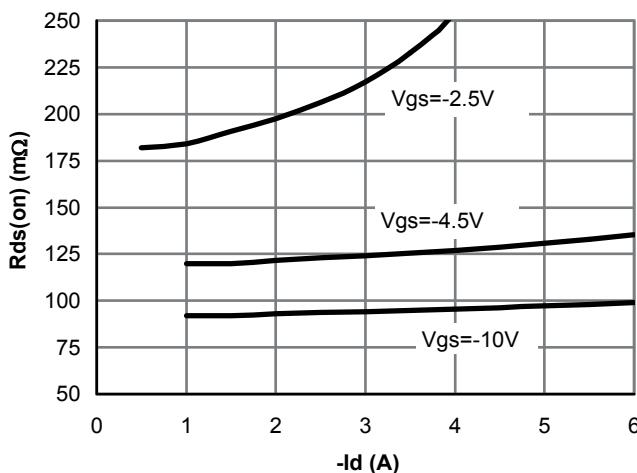
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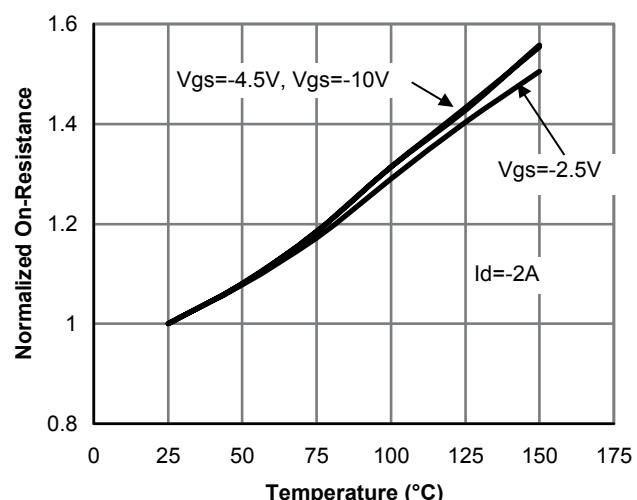
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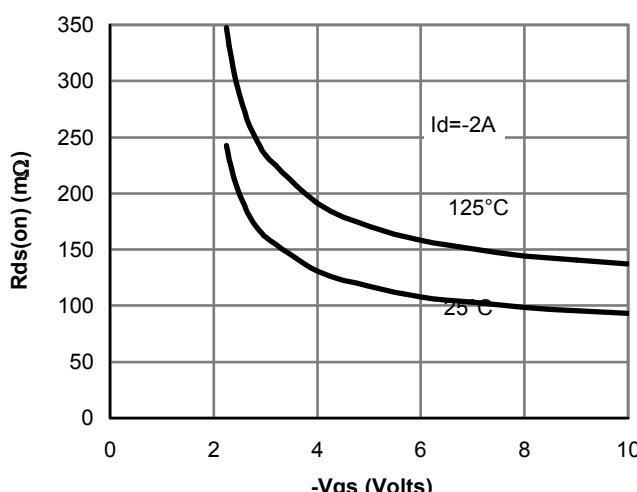
**Figure 2: Transfer Characteristics**



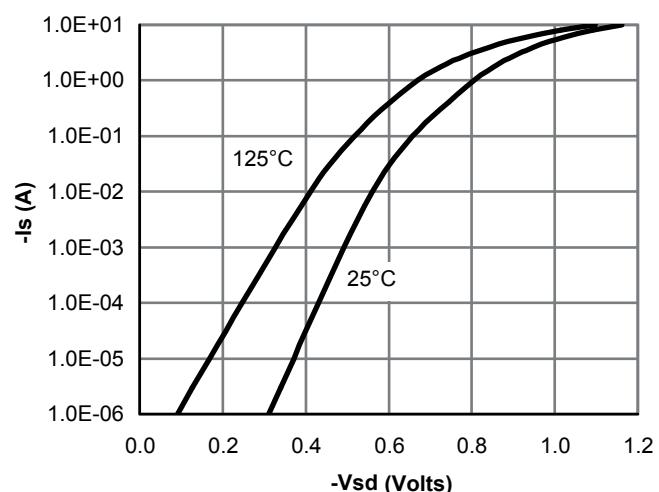
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**Figure 4: On-Resistance vs. Junction Temperature**



**Figure 5: On-Resistance vs. Gate-Source Voltage**



**Figure 6: Body-Diode Characteristics**

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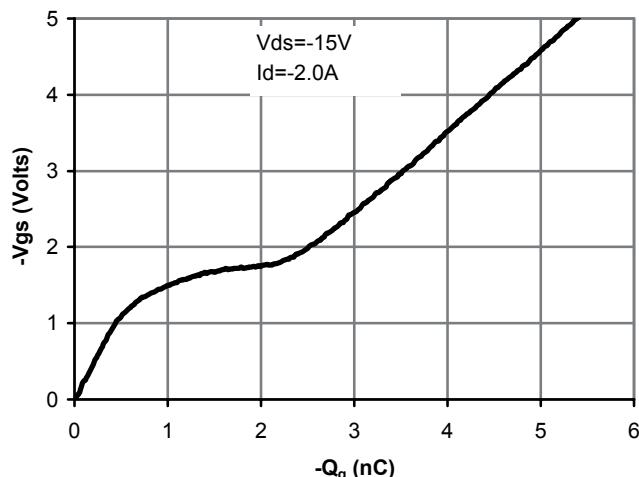


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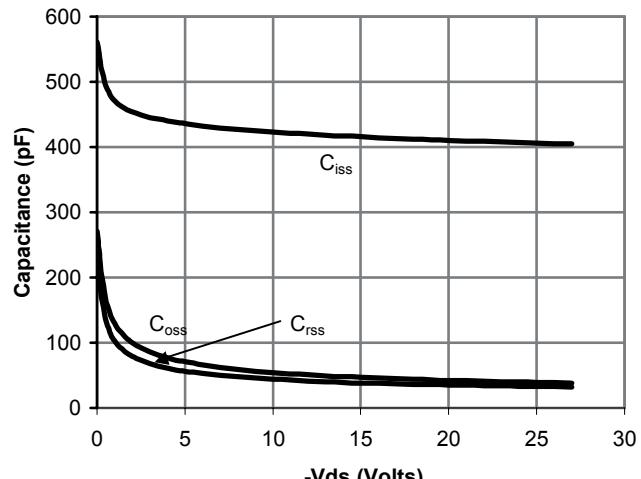


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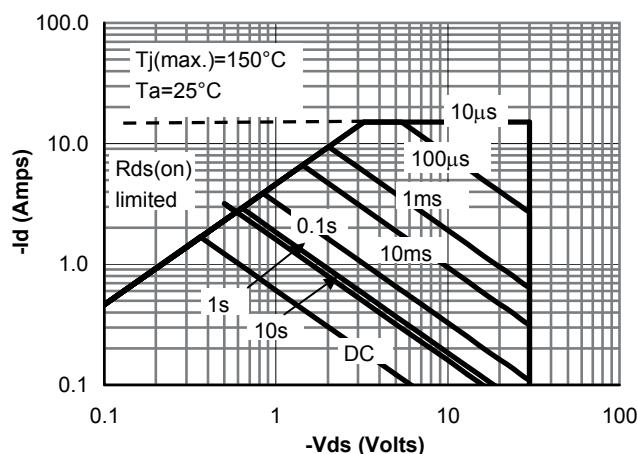


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

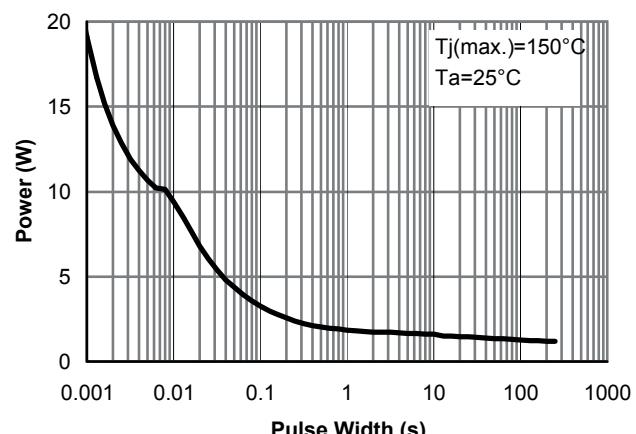


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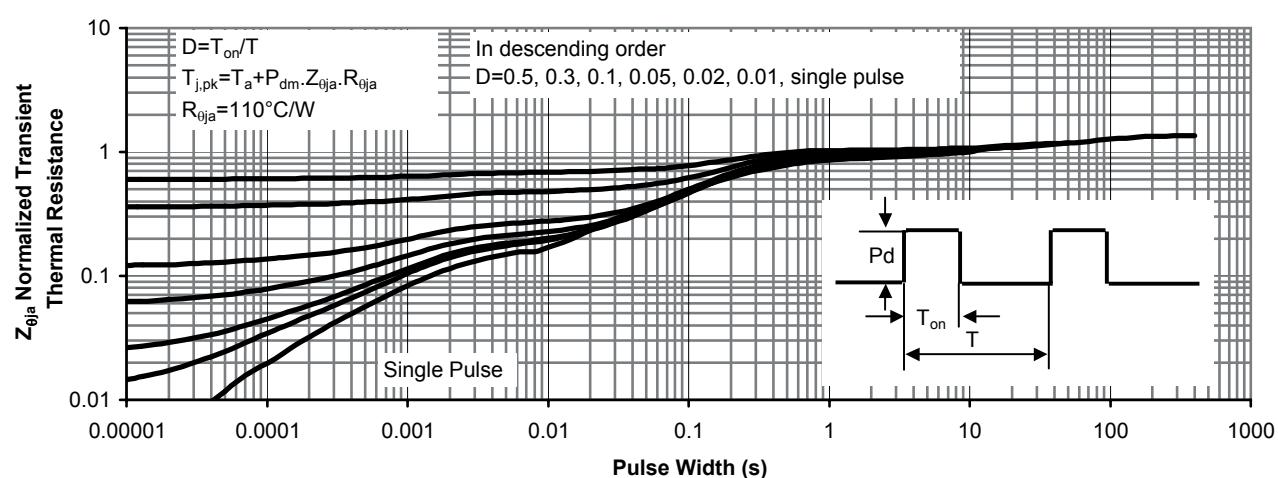


Figure 11: Normalized Maximum Transient Thermal Impedance